



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005  
& ANSI/NCSL Z540-1-1994

MENTOR TECHNICAL GROUP METROLOGY LAB  
 Caguas Real #100  
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CALIBRATION

Valid To: June 30, 2018

Certificate Number: 3595.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations<sup>1</sup>:

I. Chemical

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Conductivity Indicators <sup>3</sup> , Fixed Points	5 µS/cm 10 µS/cm 100 µS/cm 1000 µS/cm 1413 µS/cm	0.47 µS/cm 0.3 µS/cm 2.3 µS/cm 20 µS/cm 29 µS/cm	Conductivity standard solution
pH Indicators <sup>3</sup> , Fixed Points	4.00 pH unit 7.00 pH unit 10.00 pH unit	0.012 pH units 0.011 pH units 0.011 pH units	pH buffer solution

II. Dimensional

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Calipers <sup>3</sup>	(0.1 to 2) in (2 to 8) in (8 to 12) in	84 µin (66 + 10L) µin (47 + 12L) µin	ASME B89.1.9 Grade 0 gage blocks (inch)

Parameter/Equipment	Range	CMC <sup>2,4</sup> ( $\pm$ )	Comments
Calipers <sup>3</sup> (cont)	Up to 100 mm	$(6 + 2L) \mu\text{m}$	ASME B89.1.9 Grade 0 gage blocks (metric)
Micrometers <sup>3</sup>	Up to 1.0 in	$(44 + 4.8L) \mu\text{in}$	ASME B89.1.9 Grade 0 gage blocks (metric)

### III. Electrical – DC/Low Frequency

Parameter/Equipment	Range	CMC <sup>2,5</sup> ( $\pm$ )	Comments
DC Voltage – Generate	(0 to 329.999) mV (0.33 to 3.299) V (3.3 to 32.999) V (33 to 329.999) V (330 to 1020) V	55 $\mu\text{V/V} + 3.0 \mu\text{V}$ 41 $\mu\text{V/V} + 5 \mu\text{V}$ 42 $\mu\text{V/V} + 50 \mu\text{V}$ 44 $\mu\text{V/V} + 500 \mu\text{V}$ 0.044 mV/V + 1.5 mV	Fluke 5500A
DC Voltage – Measure <sup>3</sup>	Up to 100 mV (0.1 to 1) V (1 to 10) V (10 to 100) V (100 to 1000) V	12 $\mu\text{V/V} + 0.3 \mu\text{V}$ 8.5 $\mu\text{V/V} + 0.3 \mu\text{V}$ 8.5 $\mu\text{V/V} + 0.5 \mu\text{V}$ 12 $\mu\text{V/V} + 30 \mu\text{V}$ 13 $\mu\text{V/V} + 100 \mu\text{V}$	HP 3458A
DC Current – Generate	(0.3 to 3.29) mA (3.3 to 32.9) mA (33 to 329.9) mA 330 mA to 2 A (2 to 11) A	0.013 % + 0.05 $\mu\text{A}$ 0.008 % + 0.25 $\mu\text{A}$ 0.009 % + 3.3 $\mu\text{A}$ 0.025 % + 44 $\mu\text{A}$ 0.05 % + 330 $\mu\text{A}$	Fluke 5500A
DC Current – Clamp-On Ammeter (Non-Toroidal Type)	(15 to 150) A (150 to 550) A	1.3 A 3.4 A	Fluke 5500A with 5500A/coil
DC Current - Clamp-On Ammeter (Toroidal & Other Types of Clamp)	(15 to 150) A (150 to 550) A	1.3 A 3.4 A	Fluke 5500A with 5500A/coil

Parameter/Equipment	Range	CMC <sup>2,5</sup> (±)	Comments
DC Current – Measure <sup>3</sup>	100 nA to 10 µA (10 to 100) µA 100 µA to 10 mA (10 to 100) mA 100 mA to 1 A	22 µA/A + 0.14 nA 19 µA/A + 1.0 nA 24 µA/A + 58 nA 41 µA/A + 12 µA 0.013 % + 12 µA	HP 3458A
DC High Voltage – Measure <sup>3</sup>	(1 to 2) kV (2 to 10) kV	1.0 V 5.0 V	JRL KVVB-10-1, Agilent 34401A

Parameter/Range	Frequency	CMC <sup>2,5</sup> (±)	Comments
AC Voltage – Generate  (1 to 32.999) mV	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.27 % + 20 µV 0.12 % + 20 µV 0.17 % + 20 µV 0.19 % + 20 µV 0.27 % + 33 µV 0.77 % + 60 µV	Fluke 5500A
(33 to 329.999) mV	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.19 % + 50 µV 0.038 % + 20 µV 0.077 % + 20 µV 0.12 % + 40 µV 0.18 % + 170 µV 0.54 % + 330 µV	
330 mV to 3.2999 V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.12 % + 250 µV 0.023 % + 60 µV 0.06 % + 60 µV 0.11 % + 300 µV 0.18 % + 1700 µV 0.39 % + 3300 µV	
(3.3 to 32.999) V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.11 % + 2.5 mV 0.031 % + 0.6 mV 0.062 % + 2.6 mV 0.11 % + 5.0 mV 0.18 % + 17 mV	

Parameter/Range	Frequency	CMC <sup>2,5</sup> (±)	Comments
AC Voltage – Generate (cont)			
(33 to 329.999) V	45 Hz to 1 kHz (1 to 10) kHz (10 to 20) kHz	0.04 % + 2.6 mV 0.06 % + 6.6 mV 0.07 % + 33 mV	Fluke 5500A
(330 to 1000) V	45 Hz to 1 kHz (1 to 5) kHz (5 to 8) kHz	0.04 % + 80 mV 0.16 % + 100 mV 0.16 % + 100 mV	
AC Current – Generate			
(0.33 to 3.2999) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.30 % + 0.3 µA 0.27 % + 0.3 µA 0.26 % + 0.3 µA 0.29 % + 0.3 µA 0.56 % + 0.3 µA	Fluke 5500A
(3.3 to 32.9999) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.16 % + 3.0 µA 0.08 % + 3.0 µA 0.07 % + 3.0 µA 0.16 % + 3.0 µA 0.46 % + 3.0 µA	
(33 to 329.99) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) KHz	0.16 % + 30 µA 0.08 % + 30 µA 0.08 % + 30 µA 0.16 % + 30 µA 0.47 % + 30 µA	
(0.33 to 2.1999) A	(10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz	0.16 % + 0.58 mA 0.08 % + 0.66 mA 0.58 % + 1.4 mA	
(2.2 to 11) A	(45 to 65) Hz (65 to 500) Hz 500 Hz to 1 kHz	0.05 % + 2 mA 0.08 % + 2 mA 0.26 % + 2 mA	

Parameter/Range	Frequency	CMC <sup>2,5</sup> (±)	Comments
AC Current - Clamp-On Ammeter (Non-Toroidal Type)			Fluke 5500A with 5500A/coil
(20 to 150) A	(45 to 65) Hz (65 to 440) Hz	0.37 A 0.45 A	
(150 to 550) A	(45 to 65) Hz	0.52 A	
AC Current - Clamp-On Ammeter (Toroidal & Other Types of Clamp)			Fluke 5500A with 5500A/coil
(15 to 150) A	(45 to 65) Hz (65 to 440) Hz	1.8 A 2.4 A	
(150 to 550) A	(45 to 65) Hz	4.1 A	
AC Voltage – Measure <sup>3</sup>			Agilent 3458A
(0 to 10) mV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.05 % + 3 μV 0.03 % + 1.1 μV 0.04 % + 1.1 μV 0.13 % + 1.1 μV 0.51 % + 1.1 μV 4.0 % + 2.0 μV	
(10 to 100) mV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.014 % + 4.0 μV 0.009 % + 2.0 μV 0.016 % + 2.0 μV 0.048 % + 2.0 μV 0.088 % + 2.0 μV 0.30 % + 10 μV	
(10 to 100) mV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.011 % + 40 μV 0.009 % + 20 μV 0.016 % + 20 μV 0.033 % + 20 μV 0.08 % + 20 μV 0.31 % + 100 μV	

Parameter/Range	Frequency	CMC <sup>2,5</sup> (±)	Comments
AC Voltage – Measure <sup>3</sup> (cont)			Agilent 3458A
(1 to 10) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.014 % + 400 μV 0.008 % + 200 μV 0.015 % + 200 μV 0.032 % + 200 μV 0.08 % + 200 μV	
(10 to 100) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz	0.021 % + 4.0 mV 0.021 % + 2.0 μV 0.023 % + 2.0 μV	
100 V to 1 kV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 10) kHz	0.04 % + 30 mV 0.04 % + 15 mV 0.06 % + 15 mV	
AC Current – Measure <sup>3</sup>			Agilent 3458A
Up to 100 μA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz	0.43 % + 0.03 μA 0.18 % + 0.03 μA 0.09 % + 0.03 μA	
100 μA to 100 mA	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz	0.42 % + 20 μA 0.17 % + 20 μA 0.08 % + 20 μA 0.05 % + 20 μA	
100 mA to 1 A	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz	0.42 % + 200 μA 0.15 % + 200 μA 0.10 % + 200 μA 0.12 % + 200 μA	

Parameter/Equipment	Range	CMC <sup>2,5</sup> (±)	Comments
Resistance – Generate	(0 to 11) Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω (330 to 1100) Ω (1.1 to 3.3) kΩ (3.3 to 11) kΩ (11 to 33) kΩ (33 to 110) kΩ (110 to 330) kΩ (330 to 1100) kΩ (1.1 to 3.3) MΩ (3.3 to 11) MΩ (11 to 33) MΩ (33 to 110) MΩ (110 to 330) MΩ	0.011 % + 8 mΩ 0.012 % + 15 mΩ 0.007 % + 15 mΩ 0.007 % + 15 mΩ 0.007 % + 60 mΩ 0.007 % + 60 mΩ 0.007 % + 600 mΩ 0.007 % + 600 mΩ 0.007 % + 600 mΩ 0.009 % + 6 Ω 0.010 % + 6 Ω 0.013 % + 55 Ω 0.012 % + 55 Ω 0.05 % + 550 Ω 0.08 % + 550 Ω 0.39 % + 5.5 kΩ 0.39 % + 17 kΩ	Fluke 5500A
Resistance <sup>3</sup> – Measure	(10 to 100) Ω (0.1 to 1) kΩ (1 to 10) kΩ (10 to 100) kΩ (0.1 to 1) MΩ (1 to 10) MΩ (10 to 100) MΩ 100 MΩ to 1 GΩ	0.0015 % + 0.5 mΩ 0.0011 % + 0.5 mΩ 0.0011 % + 5.0 mΩ 0.0012 % + 50 mΩ 0.0015 % + 2 Ω 0.005 % + 100 Ω 0.055 % + 1.0 kΩ 0.5 % + 10 kΩ	HP 3458A
Capacitance – Generate	(0.33 to 0.5) nF (0.5 to 1.1) nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 33) nF (33 to 110) nF (110 to 330) nF (330 to 1100) nF (1.1 to 3.3) μF (3.3 to 11) μF (11 to 33) μF (33 to 110) μF (110 to 330) μF (330 to 1100) μF	0.4 % + 10 pF 0.36 % + 10 pF 0.39 % + 10 pF 0.39 % + 10 pF 0.21 % + 100 pF 0.33 % + 100 pF 0.22 % + 300 pF 0.20 % + 1 nF 0.27 % + 3 nF 0.28 % + 10 nF 0.32 % + 30 nF 0.41 % + 100 nF 0.57 % + 300 nF 0.81 % + 300 nF	Fluke 5500A

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Electrical Simulation of Thermocouples <sup>3</sup> –			Fluke 5500A, Fluke 744
Type B	(600 to 800) °C (800 to 1000) °C (1000 to 1550) °C (1550 to 1820) °C	0.34 °C 0.27 °C 0.24 °C 0.26 °C	
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1000) °C	0.39 °C 0.13 °C 0.11 °C 0.13 °C 0.17 °C	
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.21 °C 0.13 °C 0.11 °C 0.14 °C 0.18 °C	
Type K	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1372) °C	0.26 °C 0.14 °C 0.13 °C 0.20 °C 0.31 °C	
Type N	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 410) °C (410 to 1300) °C	0.31 °C 0.17 °C 0.15 °C 0.14 °C 0.21 °C	
Type R	(0 to 250) °C (250 to 400) °C (400 to 1000) °C (1000 to 1767) °C	0.44 °C 0.27 °C 0.26 °C 0.31 °C	
Type S	(0 to 250) °C (250 to 1000) °C (1000 to 1400) °C (1400 to 1767) °C	0.37 °C 0.28 °C 0.29 °C 0.36 °C	
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.49 °C 0.19 °C 0.13 °C 0.11 °C	



Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Electrical Simulation of RTD –			Fluke 5500A
Pt 385, 100 Ω	(-200 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.06 °C	
	(100 to 300) °C	0.08 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 630) °C	0.10 °C	
	(630 to 800) °C	0.18 °C	
Pt 3926, 100 Ω	(-200 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.06 °C	
	(100 to 300) °C	0.08 °C	
	(300 to 400) °C	0.09 °C	
	(400 to 630) °C	0.10 °C	
Pt 3916, 100 Ω	(-200 to -190) °C	0.20 °C	
	(-190 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.06 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.07 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 600) °C	0.09 °C	
	(600 to 630) °C	0.18 °C	
Pt 385, 200 Ω	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.04 °C	
	(100 to 260) °C	0.05 °C	
	(260 to 300) °C	0.10 °C	
	(300 to 400) °C	0.11 °C	
	(400 to 600) °C	0.11 °C	
	(600 to 630) °C	0.13 °C	
Pt 385, 500 Ω	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.07 °C	
	(300 to 400) °C	0.07 °C	
	(400 to 600) °C	0.08 °C	
	(600 to 630) °C	0.09 °C	

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Electrical Simulation of RTD – (cont)			Fluke 5500A
Pt 385, 1000 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.04 °C 0.04 °C 0.04 °C 0.05 °C 0.06 °C 0.06 °C 0.06 °C 0.18 °C	
Pt Ni 385, 120 Ω (Ni 120)	(-80 to 0) °C (0 to 100) °C (100 to 260) °C	0.07 °C 0.07 °C 0.11 °C	
Cu 427, 10 Ω	(-100 to 260) °C	0.23 °C	

#### IV. Mechanical

Parameter/Equipment	Range	CMC <sup>2,6</sup> (±)	Comments
Pressure <sup>3</sup> -			
Pneumatic Medium	(0 to 500) inH <sub>2</sub> O	0.009 %	Fluke 7252i
Pneumatic Medium	(3 to 500) psig	0.071 psig	Deadweight tester
Hydraulic Medium	Up to 1000 psi (1000 to 10 000) psi	0.52 psi 5.2 psi	Digital pressure indicators
Negative Pressure <sup>3</sup> (Pneumatic Medium)	(1 to 28) inHg	0.007 inHg	Deadweight tester

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Balances/Scales <sup>3</sup>	1 mg 2 mg 5 mg 10 mg 20 mg 50 mg 100 mg 200 mg 500 mg 1 g 2 g 5 g 10 g 20 g 50 g 100 g 200 g 500 g 1 kg 2 kg 5 kg 10 kg 20 kg	0.003 mg 0.008 mg 0.014 mg 0.008 mg 0.006 mg 0.012 mg 0.007 mg 0.008 mg 0.018 mg 0.026 mg 0.015 mg 0.03 mg 0.045 mg 0.071 mg 0.1 mg 0.16 mg 0.46 mg 1.1 mg 1.5 mg 3.4 mg 39 mg 36 mg 70 mg	ASTM Class 1 weights
High Capacity Scales <sup>3</sup>	(20 to 100) kg (100 to 500) kg (500 to 1000) kg	6.8 g 60 g 72 g	NIST Class F standard weight set
Mass – Fix Points	25 kg 20 kg 10 kg 5 kg 2 kg 1 kg	32 mg 31 mg 30 mg 30 mg 30 mg 30 mg	NISTIR 6969 SOP-7 and/or SOP-8 using ASTM Class 2 weights

Parameter/Equipment	Range	CMC <sup>2,7</sup> (±)	Comments
Volume – Pipettes, Fixed Points	1.0 µL 2.0 µL 5.0 µL 10.0 µL 20.0 µL 25.0 µL 50.0 µL 100.0 µL 200.0 µL 250.0 µL 300.0 µL 500.0 µL 1000.0 µL 1250.0 µL 2000.0 µL 2500.0 µL 5000.0 µL	0.0067 µL 0.013 µL 0.033 µL 0.067 µL 0.13 µL 0.17 µL 0.36 µL 0.72 µL 1.3 µL 1.6 µL 1.9 µL 3.2 µL 6.4 µL 8.0 µL 13 µL 16 µL 32 µL	Photometry method using Artel PCS <sup>TM</sup> calibrator kit

#### V. Thermodynamics

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Temperature – Measuring Equipment	-195 °C (-80 to -40) °C (-40 to -20) °C 0.0 °C (0.0 to 100) °C (100 to 232) °C (232 to 420) °C (420 to 660) °C	0.01 °C 0.015 °C 0.014 °C 0.013 °C 0.026 °C 0.026 °C 0.042 °C 0.043 °C	SPRT (Fixed Point)  SPRT and temperature readout
Temperature – Measure <sup>3</sup>	(-195 to -80) °C (-80 to 0) °C (-40 to 0) °C (0.0 to 30) °C (30 to 100) °C (100 to 157) °C (157 to 232) °C (232 to 400) °C	0.05 °C 0.06 °C 0.06 °C 0.07 °C 0.08 °C 0.09 °C 0.10 °C 0.14 °C	PRT/TC probe and temperature readout

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Relative Humidity – Measuring Equipment	(10 to 95) % RH	1.3 % RH	Vaisala HMT333 RH transmitter
Relative Humidity – Measure <sup>3</sup>	(10 to 95) % RH	1.6 % RH	Humidity indicator

## VI. Time & Frequency

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Frequency – Measuring Equipment <sup>3</sup>	50 Hz to 20 MHz	22 µHz/Hz	Agilent 33220A, Fluke 5500A (up to 100 kHz) HP 8664A
	20 MHz to 3 GHz	2 µHz/Hz	
Frequency – Measure <sup>3</sup>	30 Hz to 225 MHz	8 µHz/Hz	Agilent 53131A
	20 MHz to 3 GHz	2 µHz/Hz	Agilent 53131A (CH1 & CH3 option)
Timers	(0 to 86 400) s	0.05 s	Agilent 53131A & Agilent 33220A
	(0 to 86 400) s	0.054 s	Timometer 4500

<sup>1</sup> This laboratory offers commercial calibration service and field calibration service.

<sup>2</sup> Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of  $k = 2$ . The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

- <sup>3</sup> Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.
- <sup>4</sup> In the statement of CMC,  $L$  is the numerical length of the device in inches or meters.
- <sup>5</sup> The measurands stated are generated using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure the measurand in the ranges indicated. CMC's are expressed as either a specific value that covers the full range or as a fraction or percent of the reading plus a fixed floor specification.
- <sup>6</sup> In the statement of CMC, percentage refers to percent of reading, unless otherwise noted.
- <sup>7</sup> CMC values for Photometric Volume Determination do not account for uncertainty due to Unit Under Test imprecision (UUT) or Intra-Laboratory variability (repeatability and reproducibility between operators), per clause 5.4, ILAC P-14.



## Accredited Laboratory

A2LA has accredited

### MENTOR TECHNICAL GROUP METROLOGY LAB

*Caguas, PR*

for technical competence in the field of

### Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCSLI Z540-1-1994 and any additional program requirements in the field of calibration. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).



Presented this 4<sup>th</sup> day of August 2016.

A handwritten signature in black ink, appearing to read "J. C. Bennett".

Senior Director of Quality & Communications  
For the Accreditation Council  
Certificate Number 3595.01  
Valid to June 30, 2018

*For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.*